Search Notes

Application/Control No

09/544,523

Examiner

Nhan T. Tran

Applicant(s)/Patent under Reexamination

LEHRMAN, MIKEL A.

Art Unit

2622

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Used previously cited references	5/4/2006	NT		
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